Artificial Intelligence Systems in Nanoscience and Nanotechnologies

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Deadline for manuscript submissions:
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Message from the Guest Editors

We are delighted to introduce and invite you to submit original manuscripts for our Special Issue. This Special Issue will provide an interdisciplinary platform for researchers and experts in AI and nanotechnology to share their latest findings, methodologies, and applications. We encourage submissions that cover topics related to AI-enabled nanoscale materials, AI-driven nanofabrication techniques, AI-assisted nanomanufacturing processes, AI-based characterization methods, and the AI-guided design of nanodevices and systems, among others.

Keywords：

- artificial intelligence
- machine learning
- deep learning
- data analytics
- ontologies
- nanoscience
- nanotechnology
- nanomaterials
- nanodevices
- nanofabrication techniques
- nanomanufacturing processes
- ethics and social dimension of AI systems and nanotechnologies in healthcare

Special Issue

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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